TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC7MH540FK,TC7MH541FK

#### Octal Bus Buffer

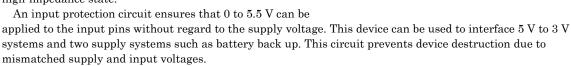
TC7MH540FK Inverted, 3-State Outputs
TC7MH541FK Non-Inverted, 3-State Outputs

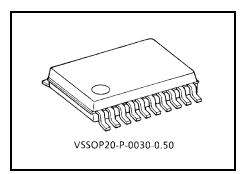
The TC7MH540FK and TC7MH541FK are advanced high speed CMOS octal bus buffers fabricated with silicon gate  $\rm C^2MOS$  technology.

They achieve the high speed operation similar to equivalent bipolar schottky TTL while maintaining the CMOS low power dissipation.

The TC7MH540FK is an inverting type, and the TC7MH541FK is a non-inverting type.

When either  $\overline{G}1$  or  $\overline{G}2$  are high, the terminal outputs are in the high-impedance state.



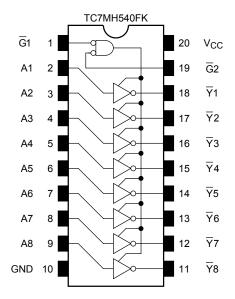


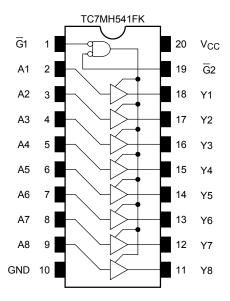
Weight: 0.03 g (typ.)

#### **Features**

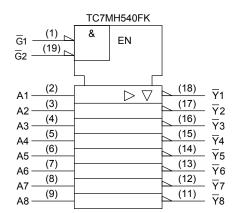
- High speed:  $t_{pd} = 3.7 \text{ ns (typ.) (VCC} = 5 \text{ V)}$
- Low power dissipation:  $ICC = 4 \mu A \text{ (max)} \text{ (Ta} = 25 \text{°C)}$
- High noise immunity: VNIH = VNIL = 28% VCC (min)
- Power down protection is provided on all inputs.
- Balanced propagation delays:  $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range: VCC (opr) = 2~5.5 V
- Low noise: VOLP = 1.0 V (max)
- Pin and function compatible with 74ALS540/541

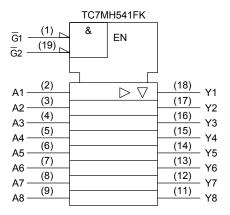
## Pin Assignment (top view)





## **IEC Logic Symbol**





#### **Truth Table**

	Inputs	Outputs				
G1	G2	An	Y <sub>n</sub> (541)	<u>Y</u> <sub>n</sub> (540)		
Н	Х	Х	Z	Z		
Х	Н	Х	Z	Z		
L	L	Н	Н	L		
L	L	L	L	Н		

X: Don't care

Z: High impedance

 $Y_n$ : TC7MH541  $\overline{Y}_n$ : TC7MH540



### **Absolute Maximum Ratings (Note)**

Characteristics	Symbol	Rating	Unit
Supply voltage range	V <sub>CC</sub>	-0.5~7.0	V
DC input voltage	V <sub>IN</sub>	-0.5~7.0	٧
DC output voltage	V <sub>OUT</sub>	-0.5~V <sub>CC</sub> + 0.5	V
Input diode current	lικ	-20	mA
Output diode current	I <sub>OK</sub>	±20	mA
DC output current	I <sub>OUT</sub>	±25	mA
DC V <sub>CC</sub> /ground current	Icc	±75	mA
Power dissipation	$P_{D}$	180	mW
Storage temperature	T <sub>stg</sub>	-65~150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## **Operating Ranges (Note)**

Characteristics	Symbol	Rating	Unit
Supply voltage	V <sub>CC</sub>	2.0~5.5	V
Input voltage	V <sub>IN</sub>	0~5.5	V
Output voltage	V <sub>OUT</sub>	0~V <sub>CC</sub>	V
Operating temperature	T <sub>opr</sub>	-40~85	°C
Input rise and fall time	dt/dv	0~100 (V <sub>CC</sub> = 3.3 ± 0.3 V)	ns/V
input rise and fail time	allav	0~20 (V <sub>CC</sub> = 5 ± 0.5 V)	115/V

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.



## **Electrical Characteristics**

## **DC Characteristics**

Characteristics		Symbol Test Condition			Ta = 25°C		Ta = -40~85°C		- Unit		
				Condition	V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Unit
			_		2.0	1.50	_	_	1.50	_	V
Input voltage	High level	V <sub>IH</sub>			3.0~5.5	V <sub>CC</sub> × 0.7	_	_	V <sub>CC</sub> × 0.7	_	
input voltage							_	0.50	_	0.50	V
	Low level	V <sub>IL</sub>	_		3.0~5.5		_	V <sub>CC</sub> × 0.3	_	V <sub>CC</sub> × 0.3	
					2.0	1.9	2.0	_	1.9	_	
	High level	Vон	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	$I_{OH} = -50 \mu A$	3.0	2.9	3.0	_	2.9	_	
Output voltage					4.5	4.4	4.5	_	4.4		V
				$I_{OH} = -4 \text{ mA}$	3.0	2.58	_	_	2.48	_	
				$I_{OH} = -8 \text{ mA}$	4.5	3.94		_	3.80	—	
Output voltage	Low level	Low level V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	$I_{OL} = 50 \mu A$	2.0	_	0	0.1		0.1	
					3.0	_	0	0.1	_	0.1	
					4.5	_	0	0.1		0.1	
				$I_{OL} = 4 \text{ mA}$	3.0	_	_	0.36	_	0.44	
				$I_{OL} = 8 \text{ mA}$	4.5	_	_	0.36	_	0.44	
3-state output of	3-state output off-state current $I_{OZ}$ $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{OUT} = V_{CC}$ or GND		5.5	_	_	±0.25	_	±2.50	μΑ		
Input leakage cu	rrent	I <sub>IN</sub>	V <sub>IN</sub> = 5.5 V or GND		0~5.5	_	_	±0.1	_	±1.0	μА
Quiescent supply	Quiescent supply current $I_{CC}$ $V_{IN} = V_{CC}$ or GND		5.5	_	_	4.0	_	40.0	μΑ		



## AC Characteristics (Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition			Ta = 25°C			Ta = -40~85°C		Unit
Characteristics	Symbol	rest Condition	V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Тур.	Max	Min	Max	Offic
			3.3 ± 0.3	15	_	4.8	7.0	1.0	8.5	
Propagation delay time	t <sub>pLH</sub>		3.3 ± 0.3	50	_	7.3	10.5	1.0	12.0	ns
(TC7MH540FK)	tpHL	_	5.0 ± 0.5	15	_	3.7	5.0	1.0	6.0	115
			5.0 ± 0.5	50	_	5.2	7.0	1.0	8.0	
			3.3 ± 0.3	15	_	5.0	7.0	1.0	8.5	
Propagation delay time	t <sub>pLH</sub>		3.3 ± 0.3	50	_	7.5	10.5	1.0	12.0	ne
(TC7MH541FK)	t <sub>pHL</sub>	_	5.0 ± 0.5	15	_	3.5	5.0	1.0	6.0	ns
			5.0 ± 0.5	50	_	5.0	7.0	1.0	8.0	
	t <sub>pZL</sub> t <sub>pZH</sub>	$R_L = 1 \text{ k}\Omega$	3.3 ± 0.3	15	_	6.8	10.5	1.0	12.5	ns
3-state output enable time				50	_	9.3	14.0	1.0	16.0	
3-state output eriable time			5.0 ± 0.5	15	_	4.7	7.2	1.0	8.5	
				50	_	6.2	9.2	1.0	10.5	
3-state output disable time	t <sub>pLZ</sub>	$R_{I} = 1 k\Omega$	$3.3 \pm 0.3$	50	_	11.2	15.4	1.0	17.5	ns
3-state output disable time	t <sub>pHZ</sub>	K[ = 1 K22	$5.0 \pm 0.5$	50	_	6.0	8.8	1.0	10.0	115
Output to output skew	t <sub>osLH</sub>	(Note 1)	$3.3 \pm 0.3$	50	_	_	1.5	_	1.5	ns
Output to output skew	tosHL	(Note 1)	$5.0\pm0.5$	50		_	1.0	_	1.0	115
Input capacitance	C <sub>IN</sub>	_	_		_	4	10	_	10	pF
Output capacitance	C <sub>OUT</sub>	-	_		_	6	_	_	_	pF
Power dissipation	0	TC7MH540FK TC7MH541FK			_	17	_	_	_	
capacitance (Note 2)	C <sub>PD</sub>			_	18	_	_	_	pF	

Note 1: Parameter guaranteed by design.

 $t_{OSLH} = |t_{pLHm} - t_{pLHn}|, t_{OSHL} = |t_{pHLm} - t_{pHLn}|$ 

Note 2: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

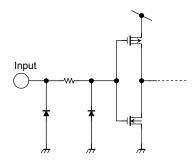
 $ICC (opr) = CPD \cdot VCC \cdot fIN + ICC/8 (per bit)$ 



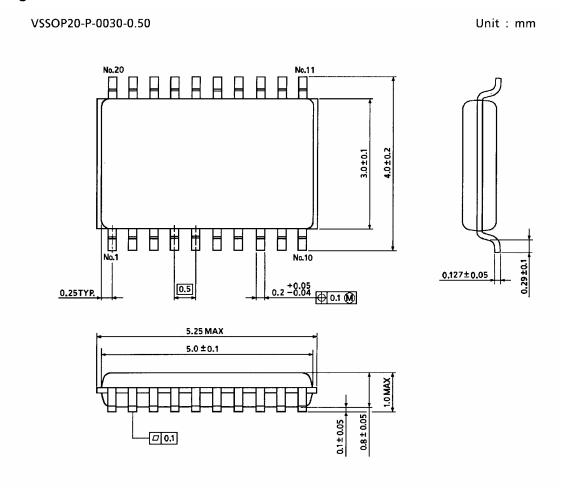
# Noise Characteristics (Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	Test Condition	Ta :		25°C	Unit
Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Тур.	Limit	Offic
Quiet output maximum dynamic V <sub>OL</sub>	VOLP	C <sub>L</sub> = 50 pF	5.0	0.7	1.0	V
Quiet output minimum dynamic V <sub>OL</sub>	V <sub>OLV</sub>	C <sub>L</sub> = 50 pF	5.0	-0.7	-1.0	٧
Minimum high level dynamic input voltage $V_{\text{IH}}$	V <sub>IHD</sub>	C <sub>L</sub> = 50 pF	5.0	_	1.5	V
Maximum low level dynamic input voltage $V_{\text{IL}}$	V <sub>ILD</sub>	C <sub>L</sub> = 50 pF	5.0		3.5	V

# **Input Equivalent Circuit**



## **Package Dimensions**



Weight: 0.03 g (typ.)

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